

# Semiconductor Solutions for 48V High Power Inverter

## Alternatives to Bare Die Modules

Eric Schütte  
Infineon Technologies AG



# Agenda

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High Power Inverters

2

Leadless SMD Packages

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Bare Dies and MOSFET Modules

4

Innovative Packaging Concepts

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Chip Embedding

6

Summary and Outlook

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Innovative Packaging Concepts

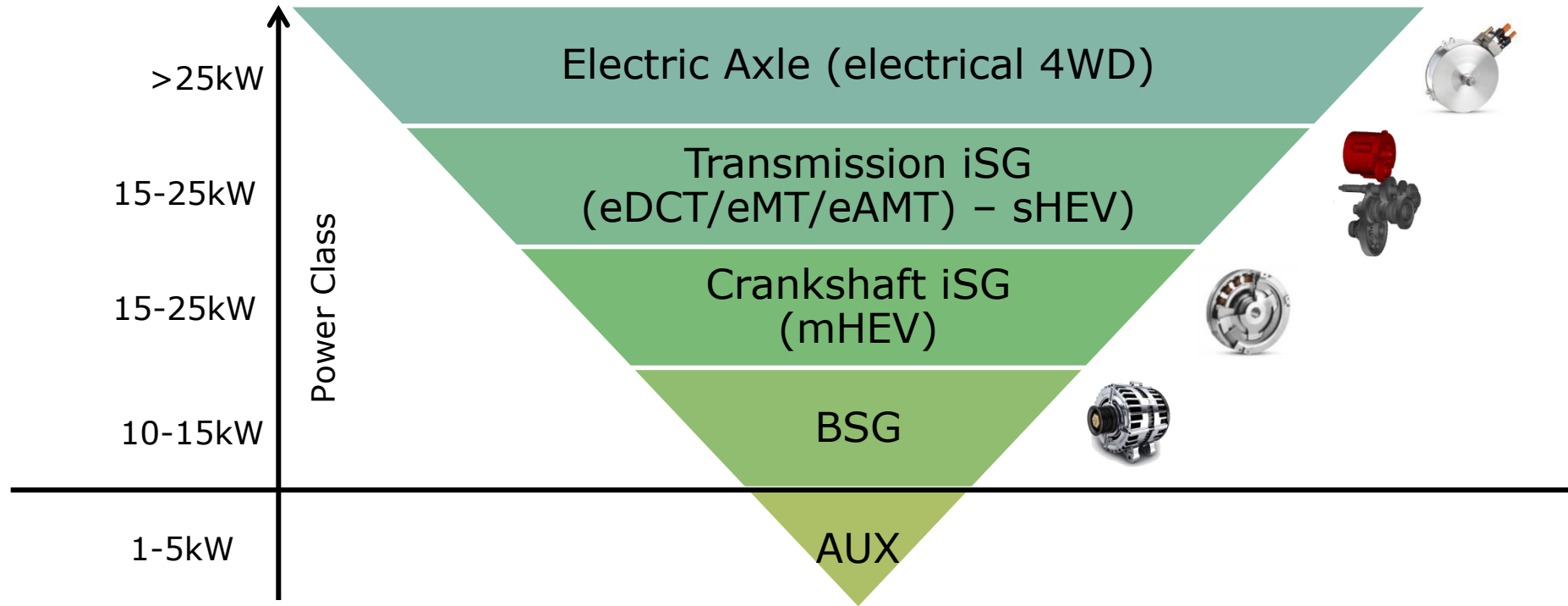
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Chip Embedding

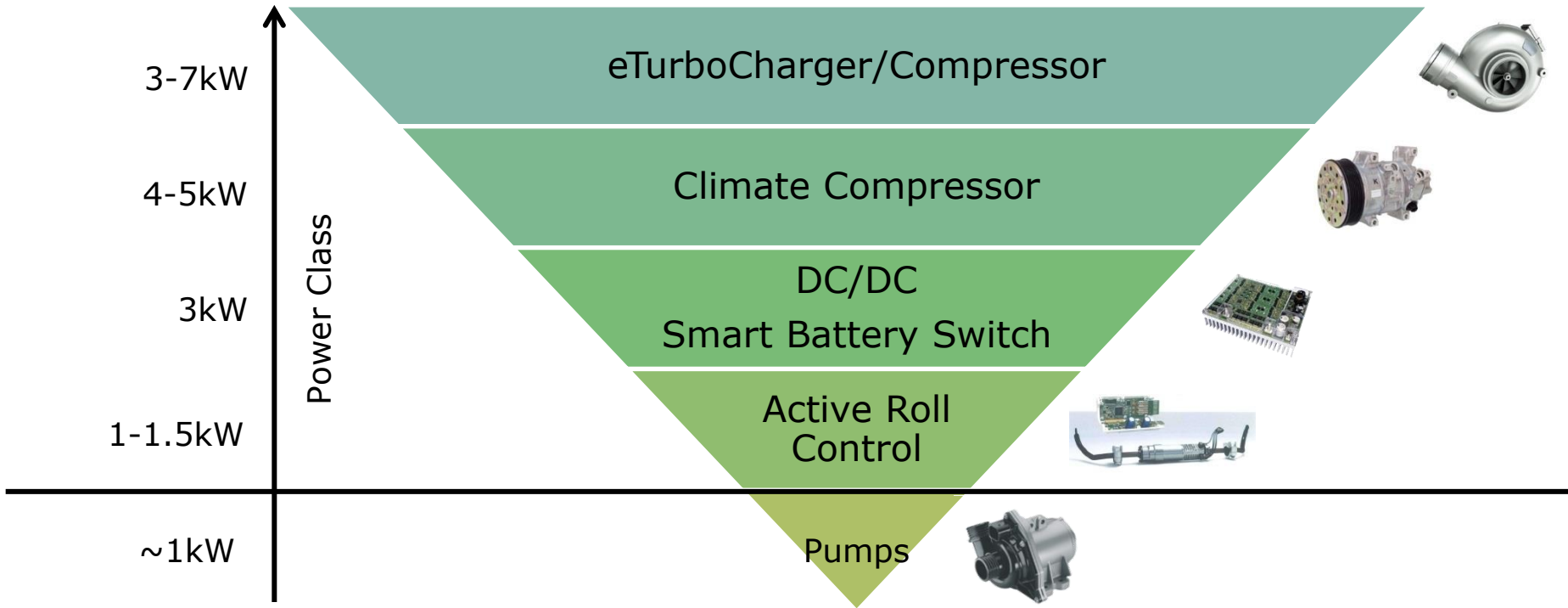
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Summary and Outlook

## > Electrification and Hybridization



# High Power Inverters Auxiliary Drives



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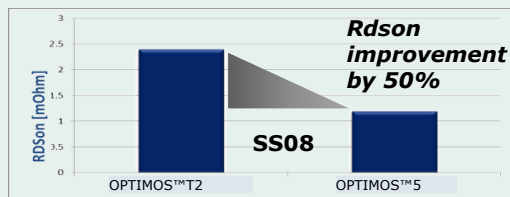
Summary and Outlook

# Leadless MOSFETs

## OptiMOS™5 80V/100V Trench Technology

### Best in Class Rdson

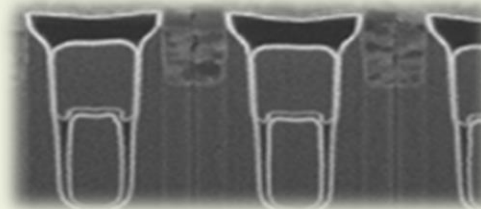
- Leading  $R_{DSon}$  performance down to 1.2mOhm (released)
- Low conduction losses
- Area reduction facilitates smaller packages



1. Applicable to normal level

### EMC Improvement

- Reduced Ciss & Coss
- Improved switching behavior
- Improved EMC behavior due to technology improvements



### Innovative package interconnect

- New top-side copper-clip contact technology
- Lower thermal resistance
- Lower package resistance
- Smaller package e.g. Achieved a footprint 1/6<sup>th</sup> the size of a DPAK for equivalent  $R_{DSon}$



# Back End Technology Portfolio and Roadmap



### SMD with cooling

**Dual side cooling**

- DirectFET2 Large-CAN**
- DirectFET2 Medium-CAN**
- DirectFET2 Small-CAN**

**Lead-less SMD**

*Focused for all new SFET Technologies*

- TOLL**
- TOLG**
- sTOLL7x8**
- S08**
- FN5x6**
- Dual FN5x6**
- Dual S08**
- S308**

### SMD with Leads

- D2PAK-7P+**
- D2PAK-7**
- D2PAK**
- DPAK**
- S08**

### Through hole

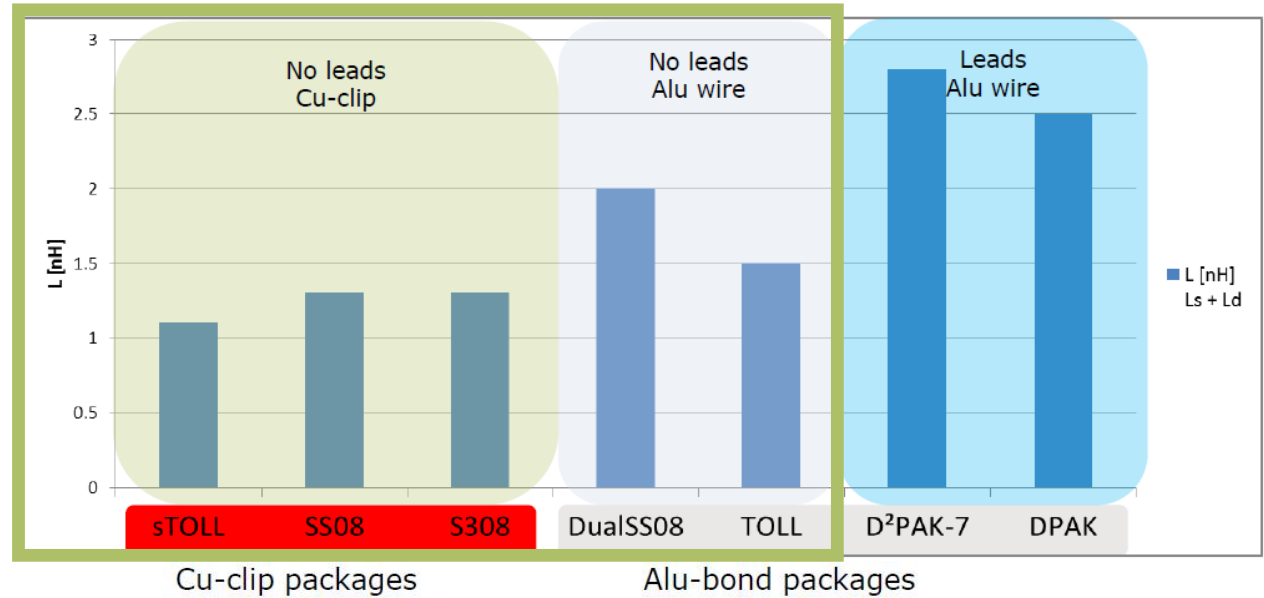
- TO262WL**
- TO247**
- TO220**
- TO262 (I2PAK)**

**Preliminary Information. Subject to change.**  
**sTOLL registered at JEDEC**



# Leadless MOSFETs Interconnect Technology

- > **Cu-Clip Packages**  
offer Lowest Package  
**Resistance &  
Inductance**
- > Best EMI Behavior
- > Lowest Voltage  
Overshoots



### **IOL=Intermittent Operating Lifetime („Power Cycling“)**

#### Testing conditions acc. AEC Q101

Start Temperature	20°C
Temperature rise during cycles	$\Delta T=100K$
Current	Applied to the bodydiode for a few seconds to heat up the chip to the target temperature
Number of tested devices	77
Number of power cycles	15.000 with no failures

#### Premisses

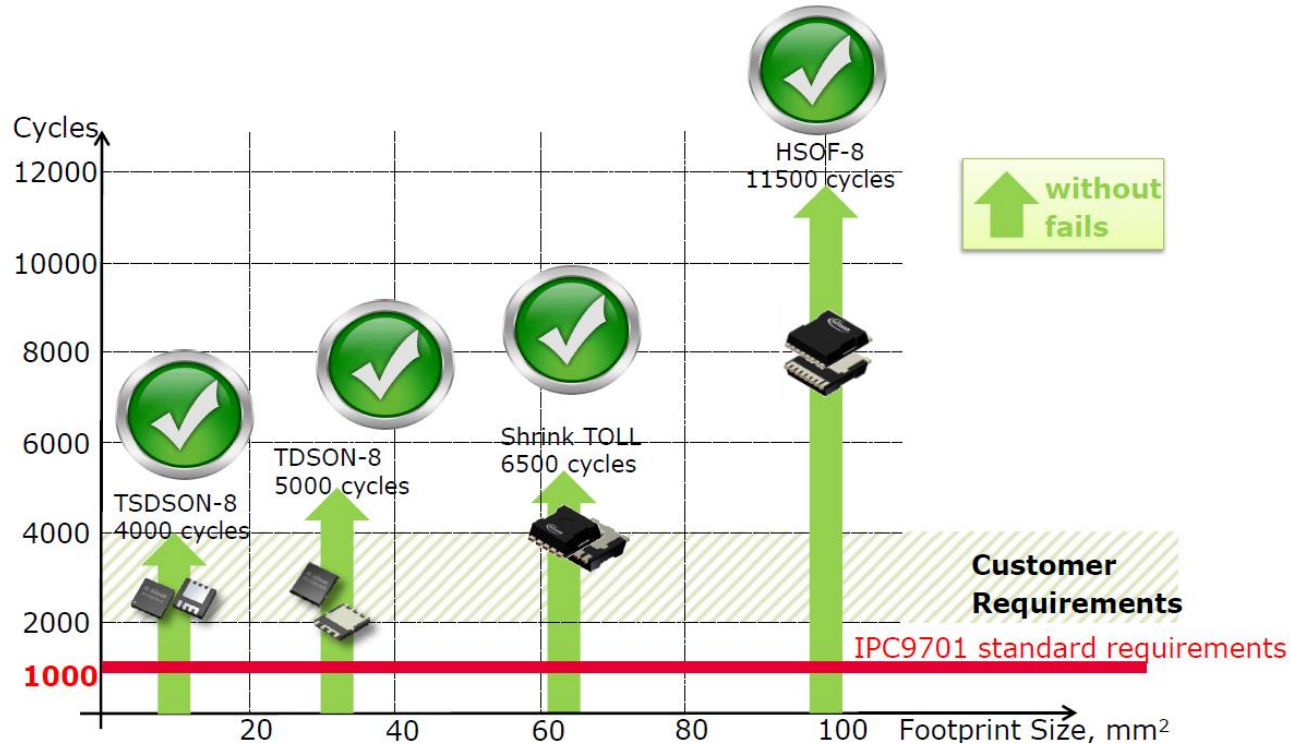
- cooling down the device needs approximately 3 minutes
- a parameter drift of 20% is considered as failure

#### Measured parameters

All standard parameters according to datasheet:  
Leakage currents,  $V_{BRDSS}$ ,  $V_{GStH}$ ,  $R_{DS(on)}$  etc.

# Robustness of Leadless Packages Beyond IPC-9701

## › Enhanced TCoB Performance



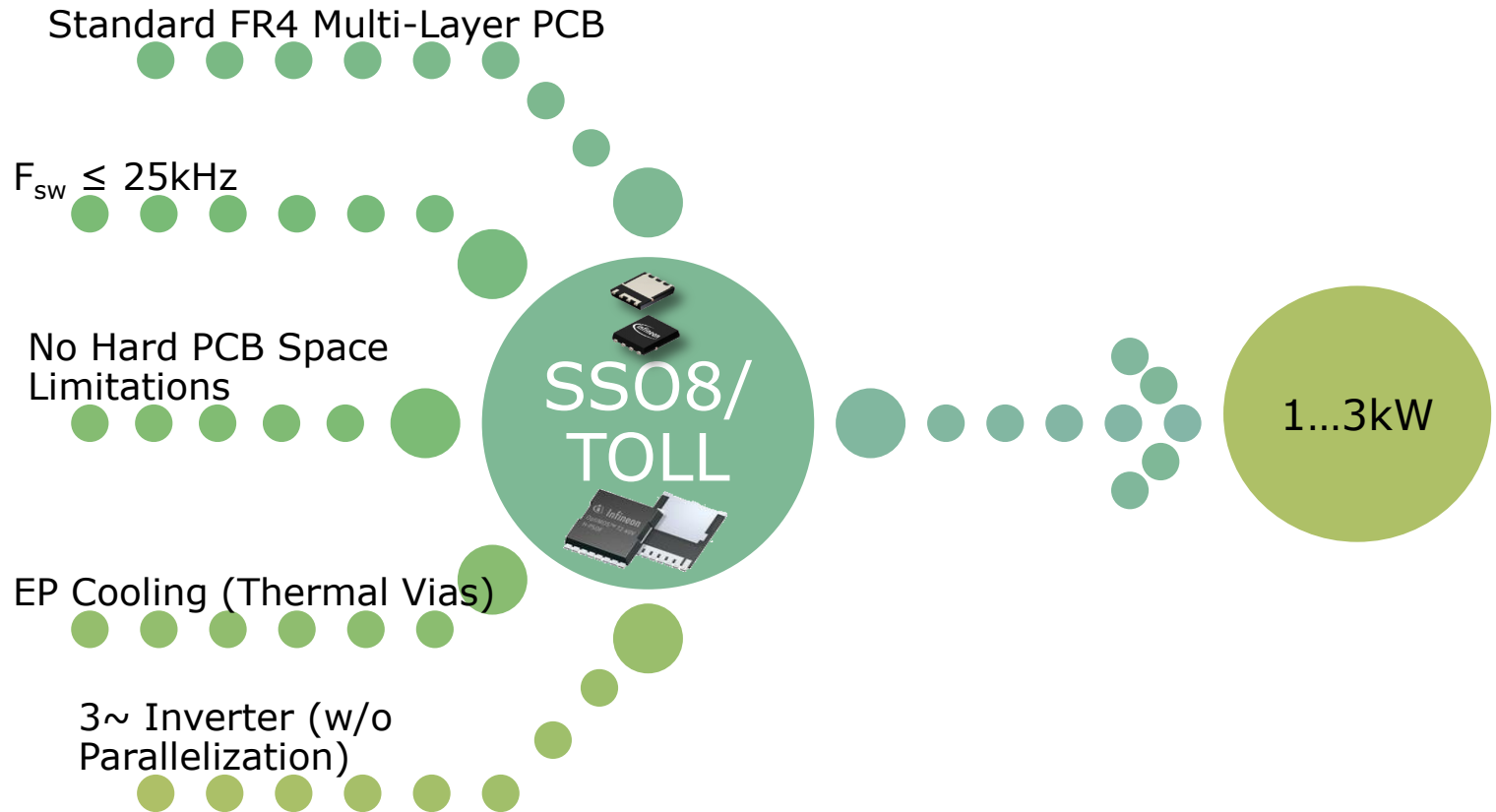
# 80V & 100V MOSFET Portfolio with Leadless Packages

	PQFN 5x6 (TDSON)	PQFN5x6 (TDSON)	SS08 (TDSON)	SS08 (TDSON)	TOLL (H-SOF)	TOLL (H-SOF)	DirectFET2 (WDSO)
Foot-Print	5x6mm	5x6mm	5x6mm	5x6mm	10x12mm	10x12mm	7x9mm <sup>2</sup>
I-Package	100A	100A	100A	100A	300A	300A	88A
Released	Gen 10.7 75V	Gen 10.7 100V	OptiMOS™5 80V	OptiMOS™5 100V	OptiMOS™5 80V	OptiMOS™5 100V	Gen10.7 100V
$R_{DSon}$ BiC	8.5mΩ	14.5mΩ	3.1mOhm	4mOhm	1.2mΩ	1.5mOhm	2.8mΩ

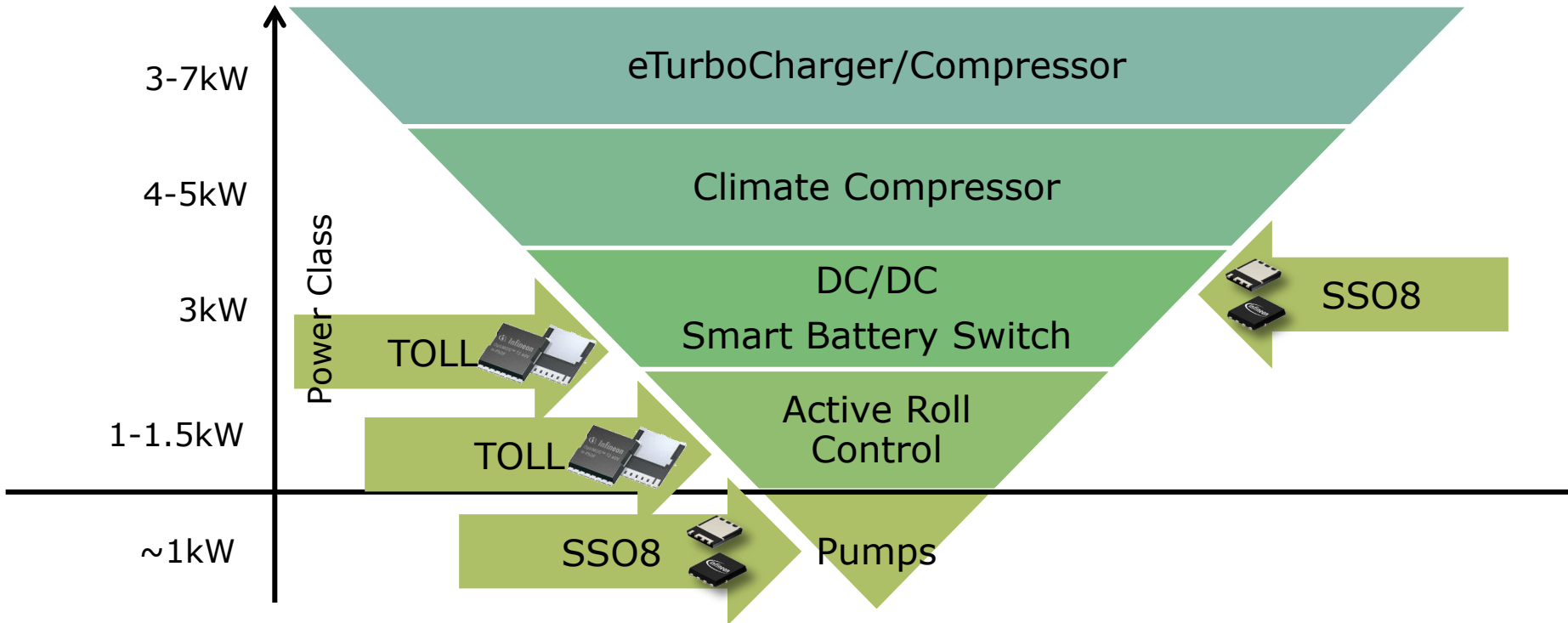
- › Suitable for standard FR4 PCBs
- › High Reliability during TCoB and IOL Tests

**Preliminary Information. Subject to change.**

# Limitations of Leadless SMD Packages System Requirements

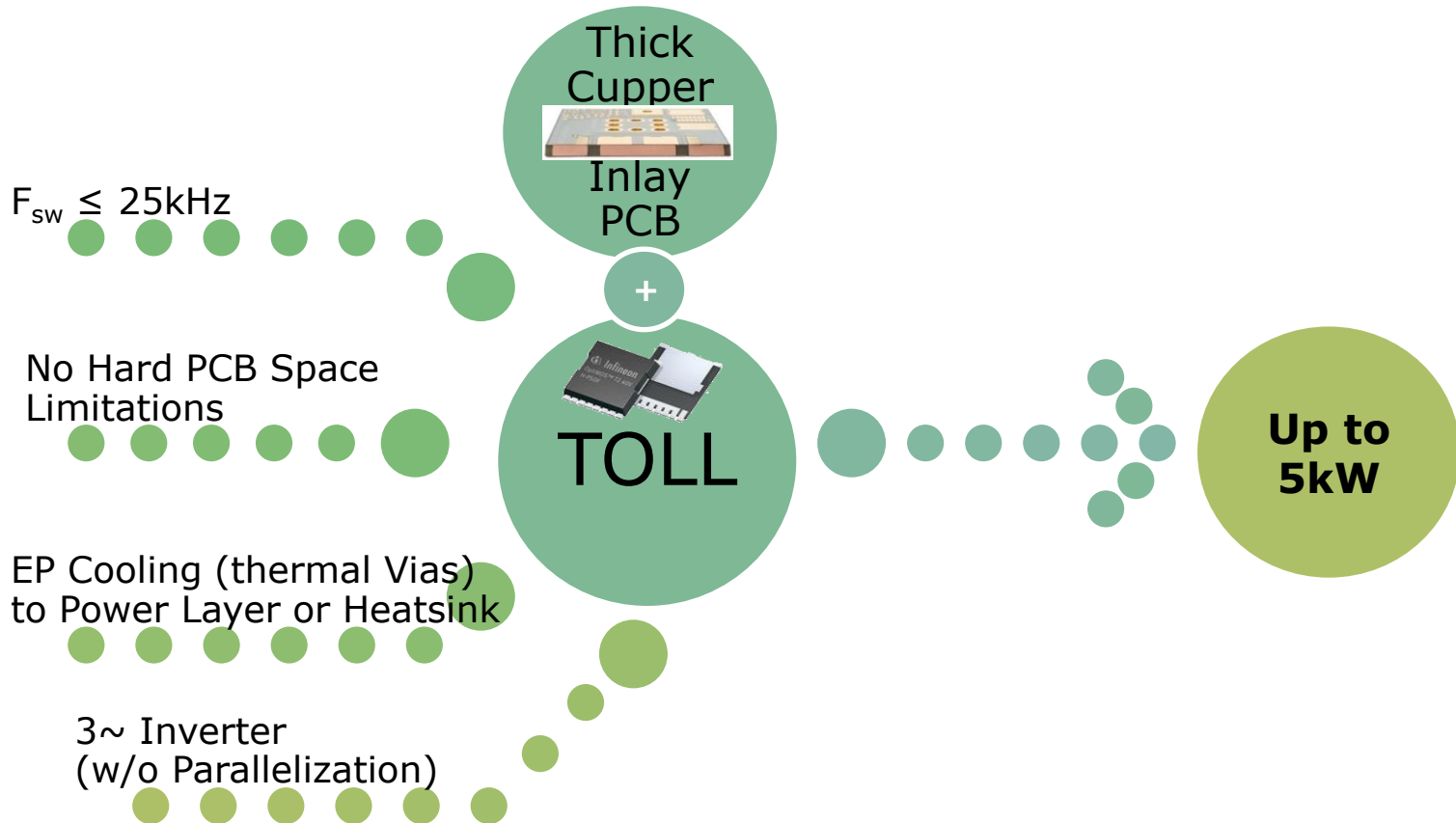


# Leadless SMD MOSFETs Auxiliary Drives

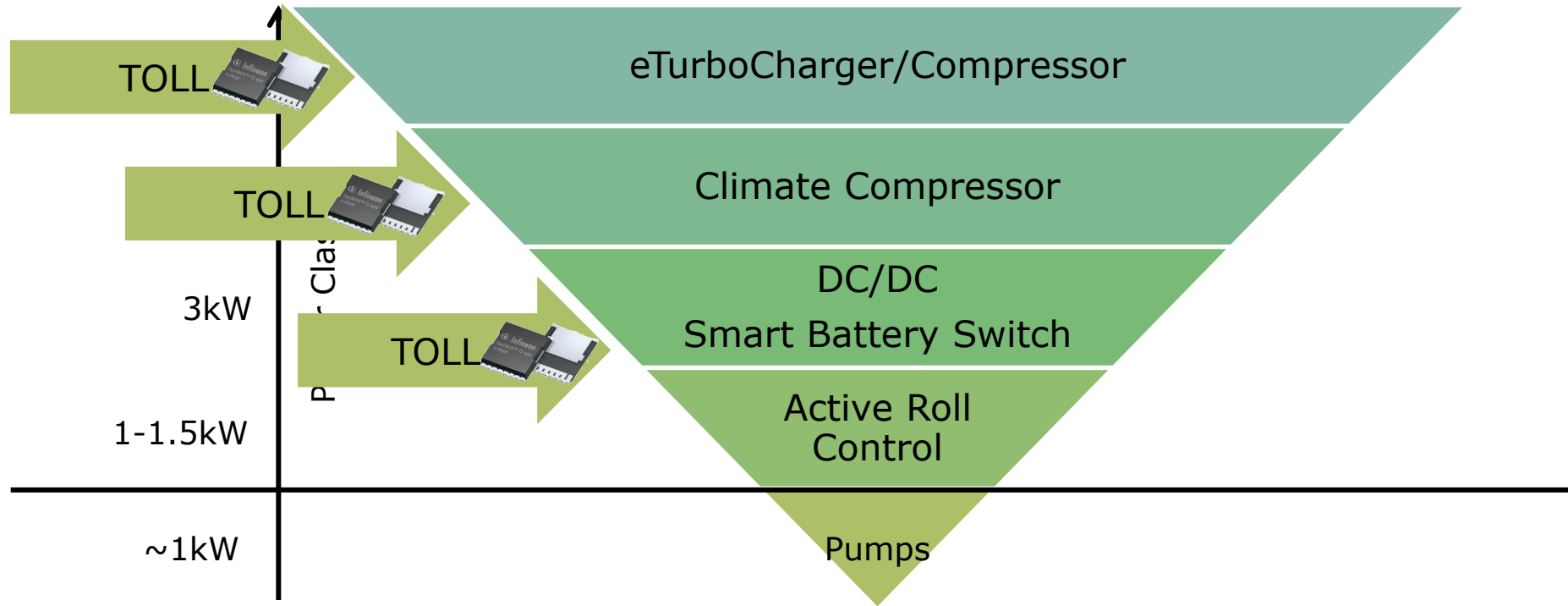


# Limitations of Leadless SMD Packages

## Increasing the Output Power with Thick Copper PCB



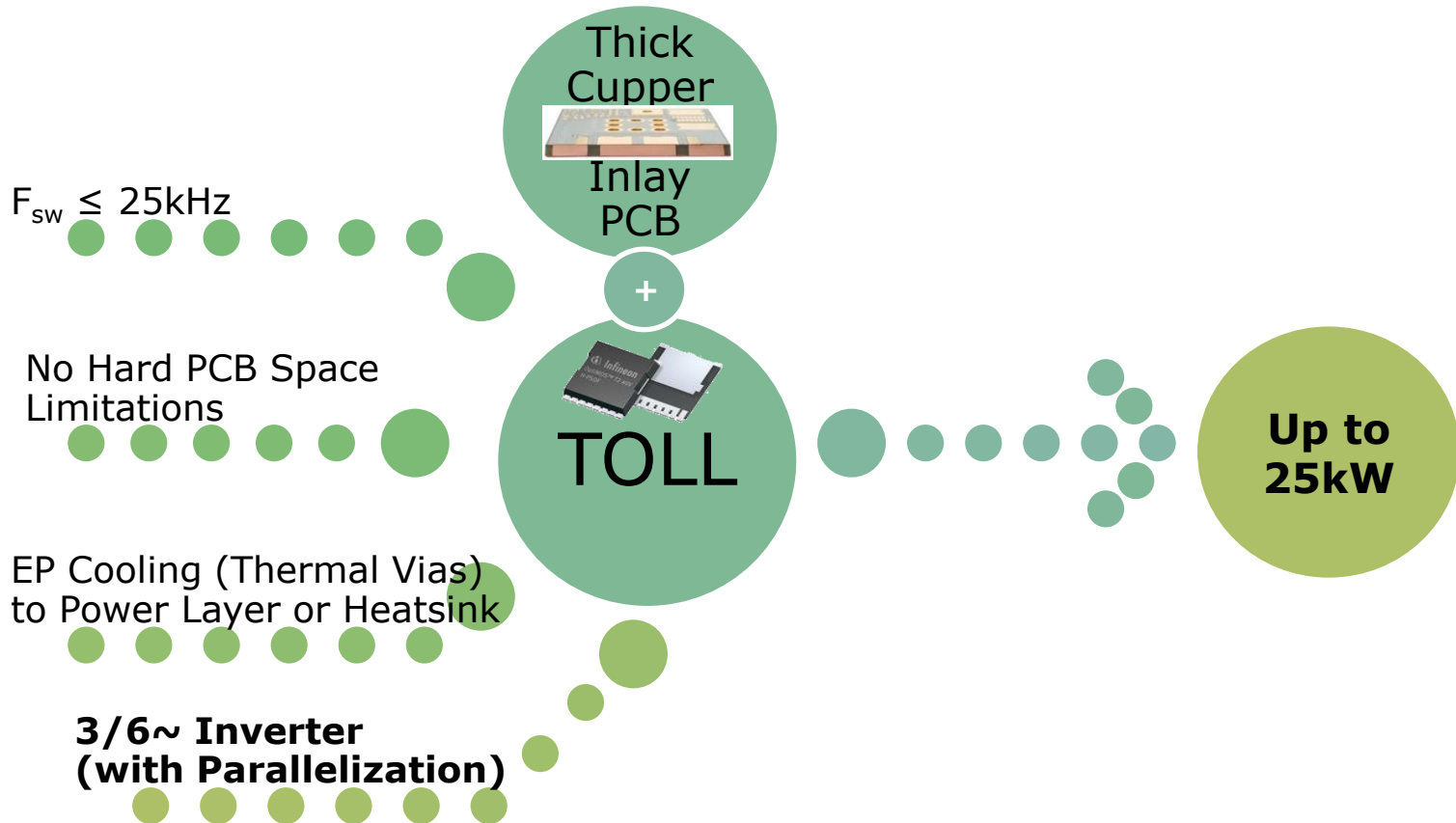
# Leadless SMD MOSFETs Auxiliary Drives





# Limitations of Leadless SMD packages

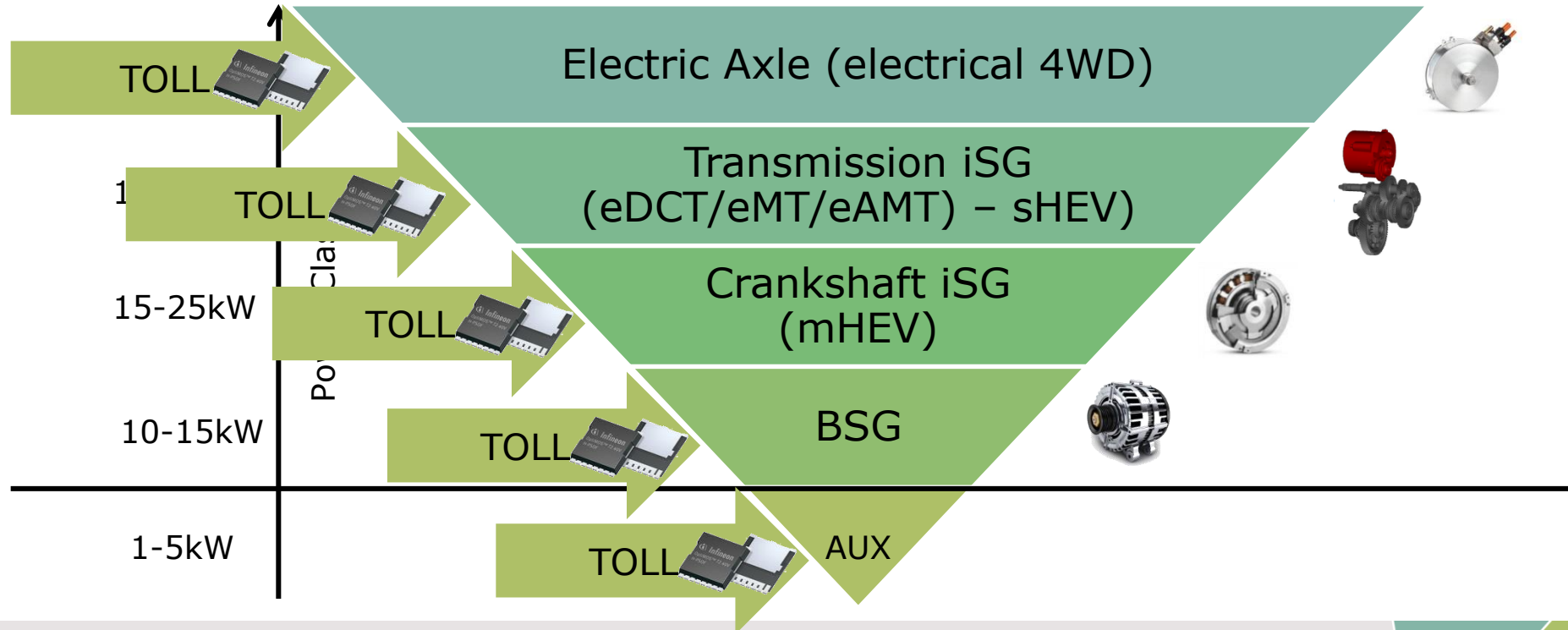
## Increasing the Output Power with Thick Copper PCB



# Leadless SMD MOSFETs High Power Inverters



## > Electrification and Hybridization



# Leadless SMD Packages Advantages

## Assembly

- > Optical Inspection
- > Standard Soldering Process (e.g. Reflow)

## Market

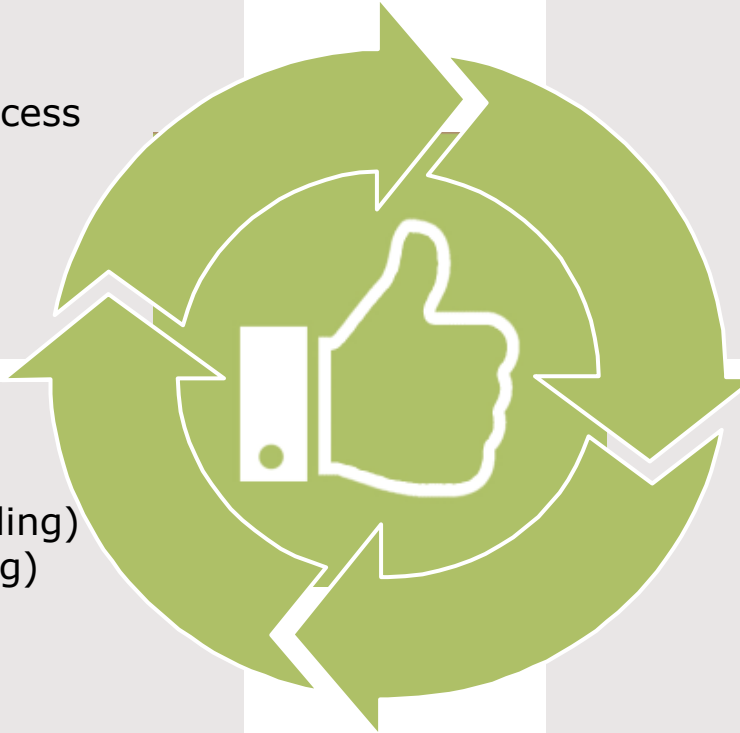
- > 2<sup>nd</sup> Source Strategy
- > Multiple, Footprint Compatible Alternatives available

## Quality

- > Fully AECQ qualified
- > Proven IOL (Power Cycling) and TCoB (Temp Cycling) Reliability

## PCB

- > Standard FR4
- > Multiple Supplier
- > Well Known Copper Technologies



# Limitations of Leadless SMD Packages

## Disadvantages

### PCB

- › Increased PCB Temperature
- › Layout Inflexibility
- › High Thermal Stress on Solder Mask (->reliability)
- › Only applicable for Copper Substrate

### Cooling

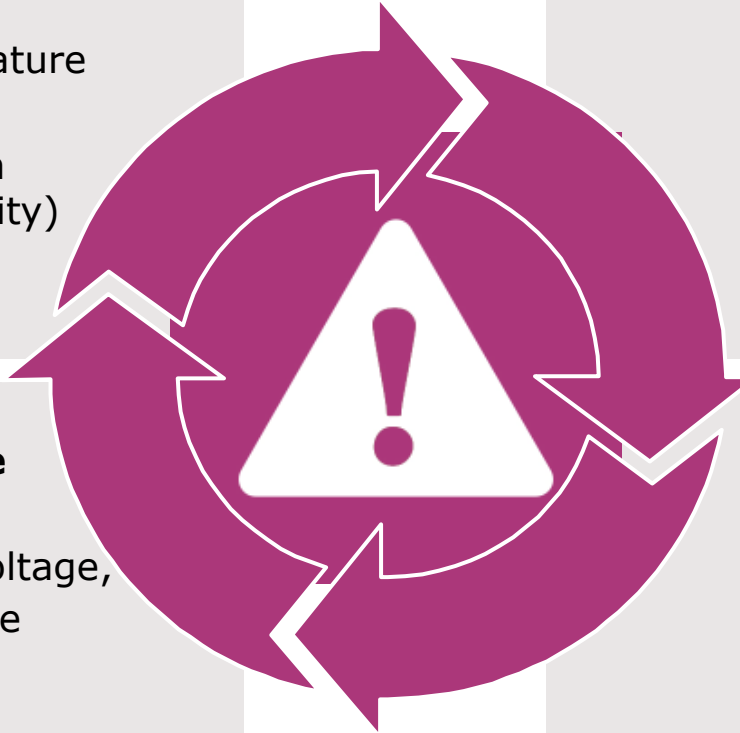
- ›  $R_{thJunction-Ambient}$  limited by Package
- › Thick Copper Layer or Inlay
- › Bottom Side Cooling

### Parallel Switching Performance

- › Parameter Variation
  - › Gate-Threshold Voltage,
  - › Breakdown Voltage

### Power

- › Limited by Bonding/Clipping (per device)



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**Bare Dies and MOSFET Modules**

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Summary and Outlook

## System Dimensions

- › Modules
- › Most Flexible Design
- › Adaptive to All Circumstances

## Power

- › Customized Chip Size

## Switching

- › Reduced Stray Inductance depending on Design

## Temperature & Cooling

- › Applicable for HOT Environments (up to 175°C)
- › Customized Cooling Approaches
- › Homogeneous Power Loss Distribution



# Bare Dies and MOSFET Modules Technical Challenges



# Bare Dies and MOSFET Modules

## Reliability: PPM Rates



### PACKAGED DEVICES

### BARE DIES

**Front End +  
Pre-assembly**

Wafer Test @IFX

Wafer Test @IFX

Escape Rate Technology & Test Coverage related

Escape Rate Technology & Test Coverage related

**Back-End/  
Assembly**

$I_{AS}$  up to 300A @IFX

$I_{AS}$  test depending on the application requirements @customer

Field return  $\sim 0.1\text{ppm}$

Failure rate after module assembly depending on customer



## Yield @ Customer

- › Yield Loss after Assembly @ Customer

## Handling

- › Thin Wafer Technology
- › Very sensitive to Cracks
- › Strongly depending on Customer's Experience

## Testing

- › Avalanche Current Testing at Customer Required
- › Need of Additional Module Stress Tests (e.g. Power & Temp Cycling)

## Assembly

- › Customer is Responsible for entire Back-End-of-Line Process



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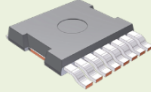
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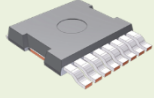
Summary and Outlook

# Innovative Packaging Concepts

## DirectFET2/TOLG/Top Side Cooling

	DirectFET2 (WDSO <sub>N</sub> )	<b>TOLG</b>
		
<b>Foot-Print</b>	7x9	10x12mm
<b>I-Package</b>	88A	300A
<b>Released</b>	Gen10.7 100V	OptiMOS™5 80V
<b><math>R_{DSon}</math> BiC</b>	2.8mΩ	1.2mΩ
	Dual Side	Bottom Side
<b>PCB/Cooling</b>	Bottom: FR4 Copper Top: Water Cooling	Bottom: FR4/Al-core IMS

**Preliminary Information. Subject to change.**

	DirectFET2 (WDSO <sub>N</sub> )	<b>TOLG</b>
		
<b>Foot-Print</b>	7x9	10x12mm
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	Dual Side	Bottom Side
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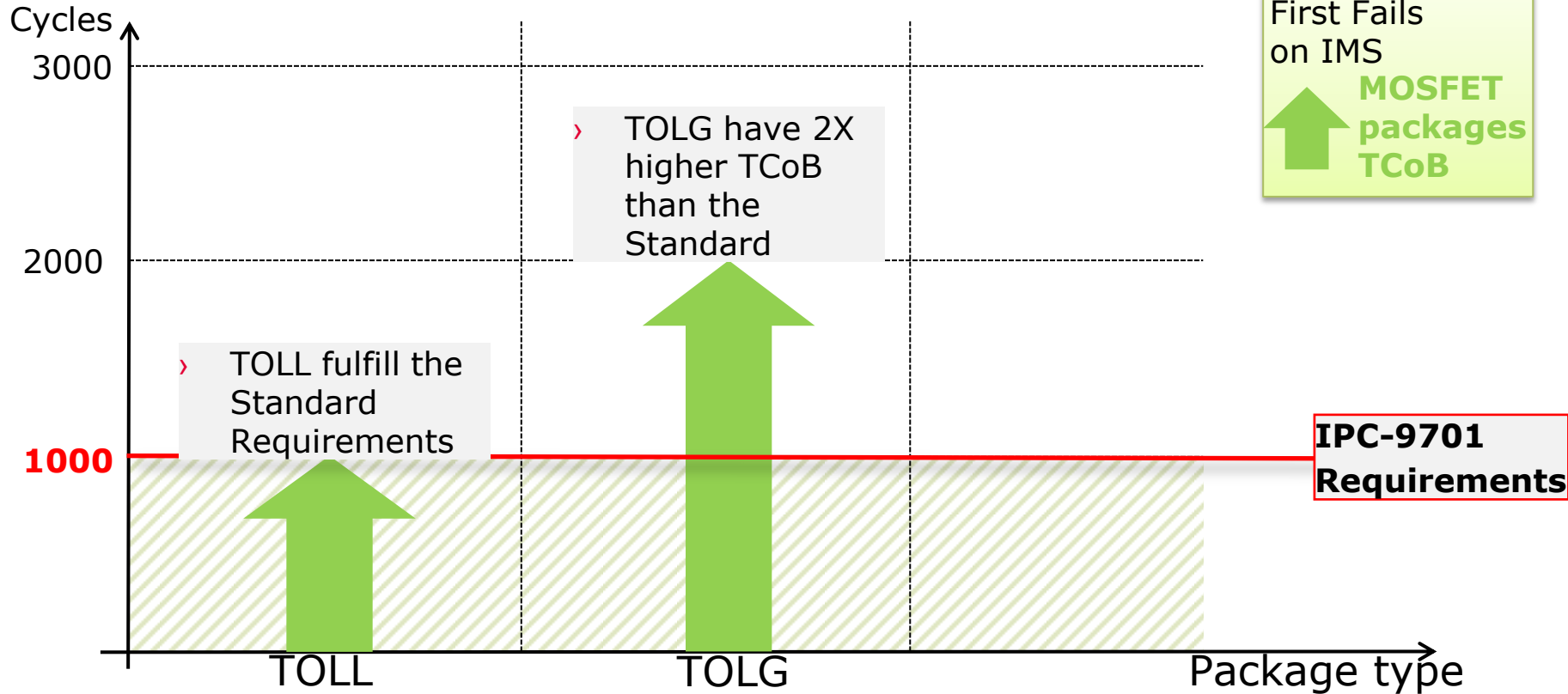
**Preliminary Information. Subject to change.**

- › Cu (based Material for the Leadframe of the MOSFET), Al and FR4 have different Coefficients of Thermal Expansion:

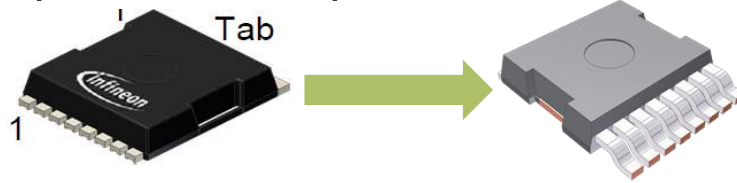


- ➔ The Mismatch between Cu and Al-Core IMS will lead to higher Stress on the Solder Material, and reduce the Robustness of the System during Thermal Cycles, which may lead to Cracks within the Solder Material
- ➔ Failure Mode: always Solder Joint Fatigue at the Corner Pins @ Gate/Source
- ➔ TOLL is appropriate for FR4 Boards and Cu-Core IMS

# TCoB Performance of TOLL and TOLG on IMS (-40°C to 125°C):

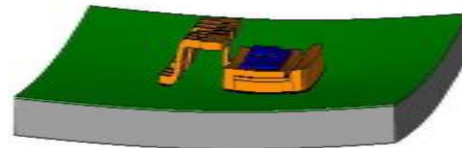
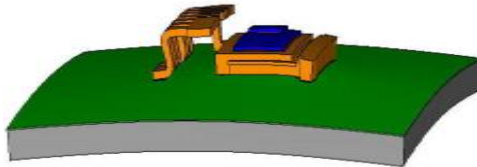


- › Infineon investigated a Derivate of the TOLL (TOLL with Gullwing Geometry) to improve TCoB performance on AI-core IMS:

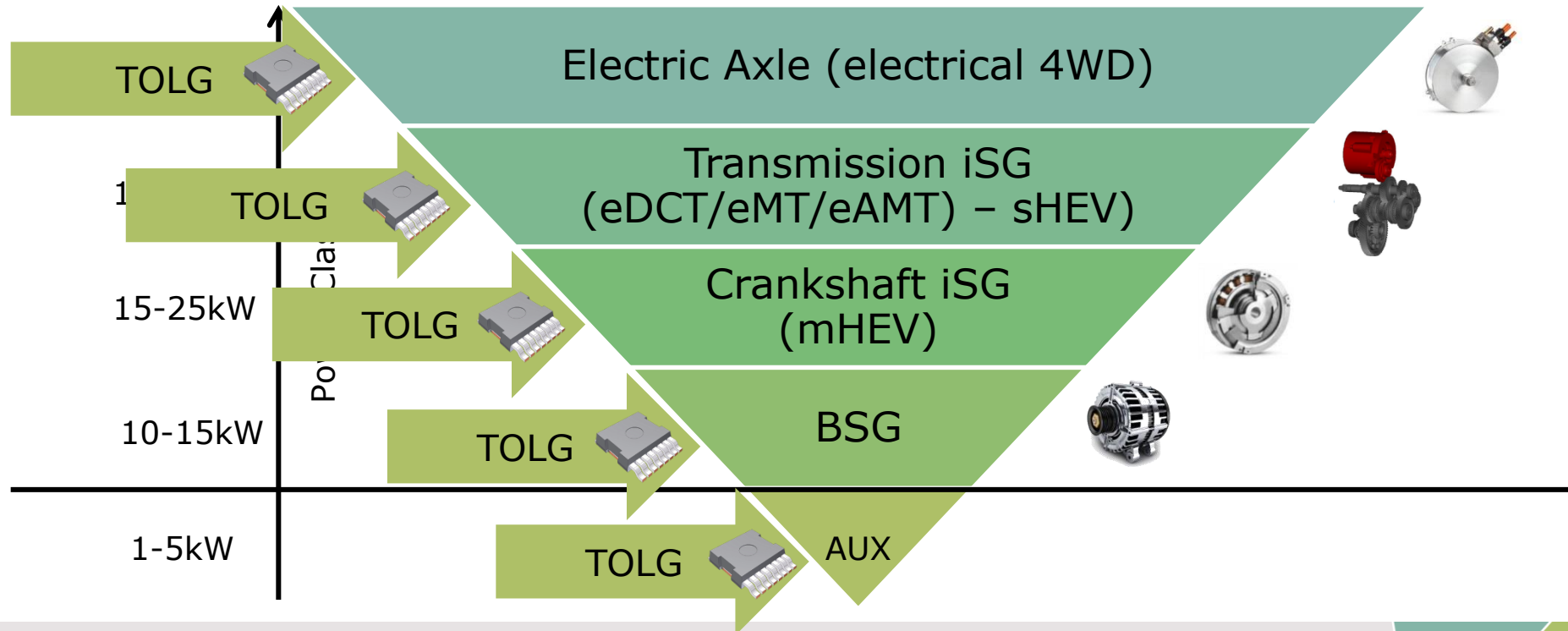


- › Results:

- On IMS: the TOLG performs much better than the TOLL under same Conditions
- Reason for better Performance is the Flexibility of the Gullwing Leads




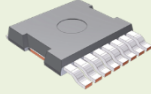
### > Electrification and Hybridization





# Innovative Packaging Concepts

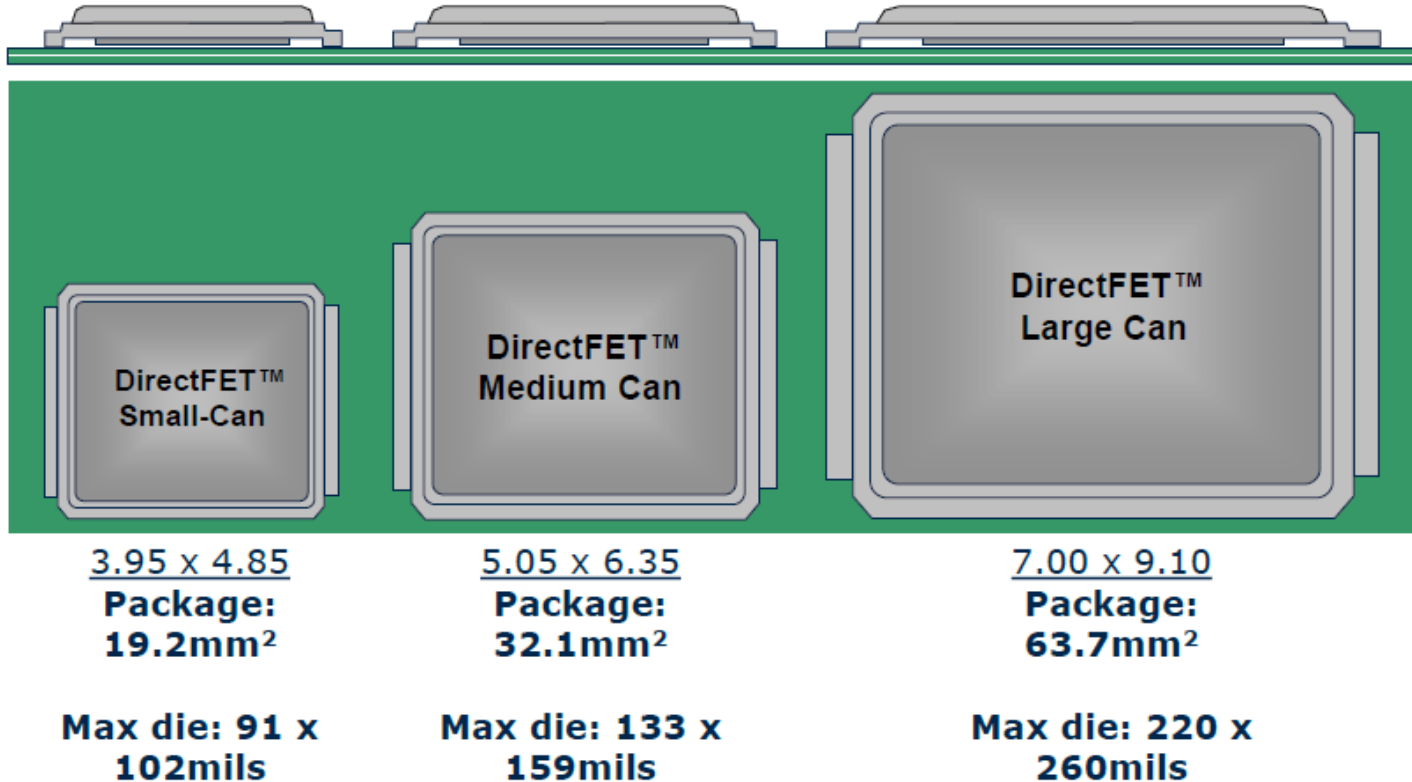
## DirectFET2

	DirectFET2 (WDSO <sub>N</sub> )	TOLG
		
<b>Foot-Print</b>	7x9mm	10x12mm
<b>I-Package</b>	88A	300A
<b>Released</b>	Gen10.7 100V	OptiMOS™5 80V
<b><math>R_{DSon}</math> BiC</b>	2.8mΩ	1.2mΩ
<b>PCB/Cooling</b>	Dual Side  Bottom: FR4 Copper Top: Water Cooling	Bottom Side  Bottom: FR4/Al-core IMS

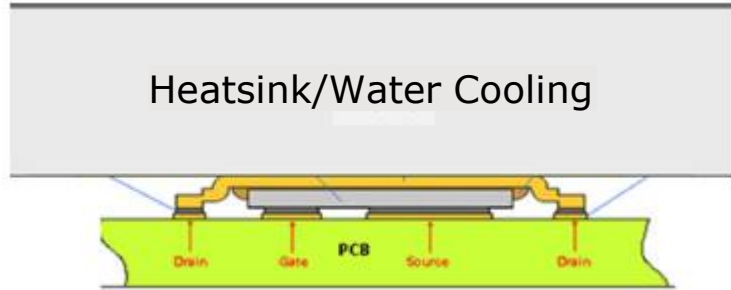
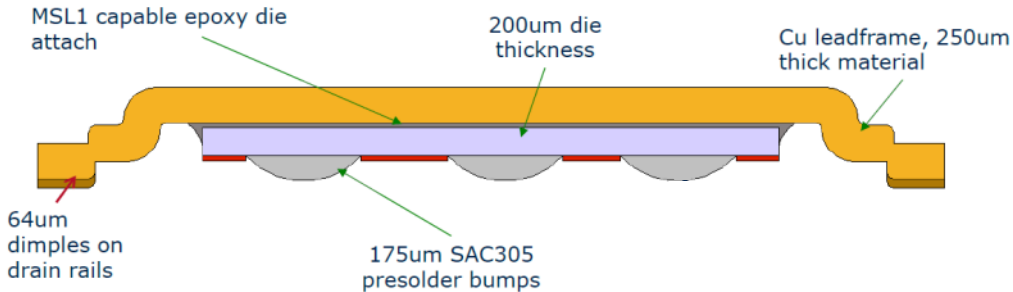
**Preliminary Information. Subject to change.**

# Innovative Packaging Concepts

## DirectFET2

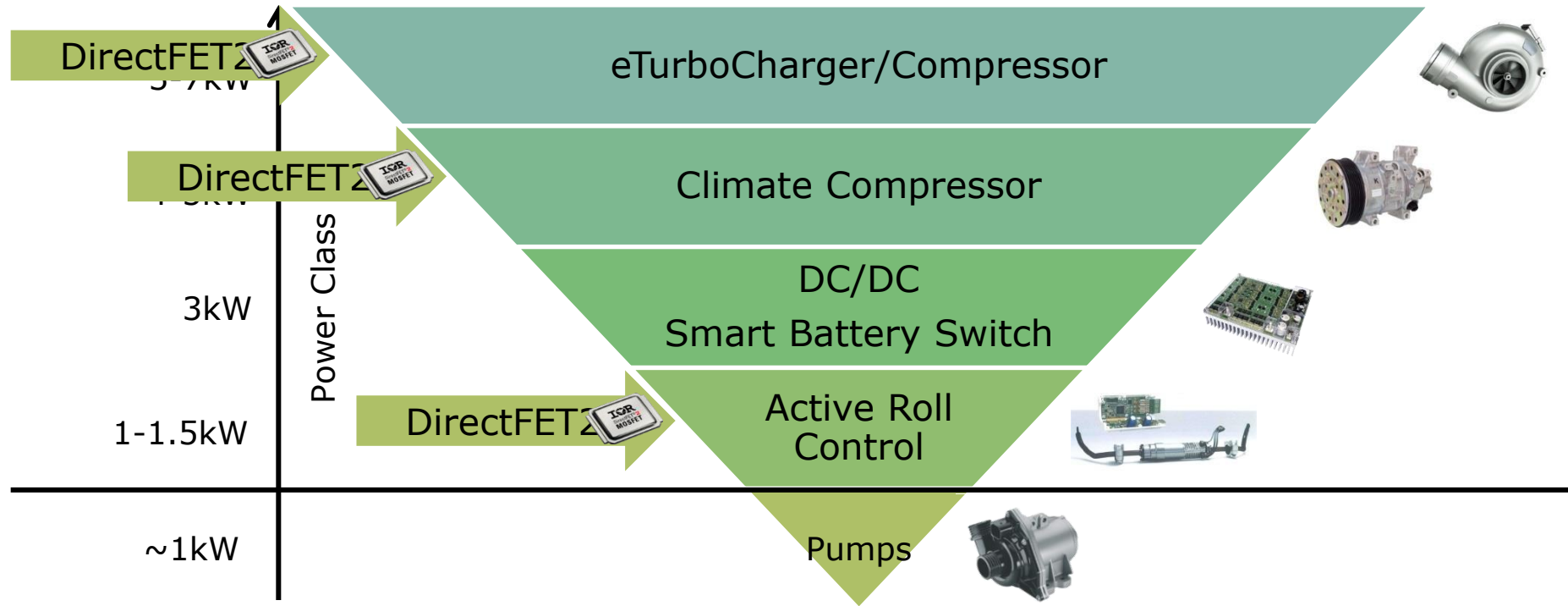


- › Allowing Double Side Cooling
  - Top-Side: Heatsink / Water Cooling
  - Bottom-Side: Thermal Vias to Power Cu Layer



DirectFET2	$V_{br}$	$R_{ds(on)}$	Package	$R_{th(JC)}$ Top	$R_{th(JA)}$ Bottom
AUIRF7669L2	100V	3.5mOhm	Large CAN	0.553 K/W	28.286 K/W
AUIRF7759L2	75V	2.3mOhm	Large CAN	0.881 K/W	26.69 K/W

# DirectFET2 Applications



## Switching

- › Lowest Stray Inductance in Class due to missing Bond Wires

## Cooling

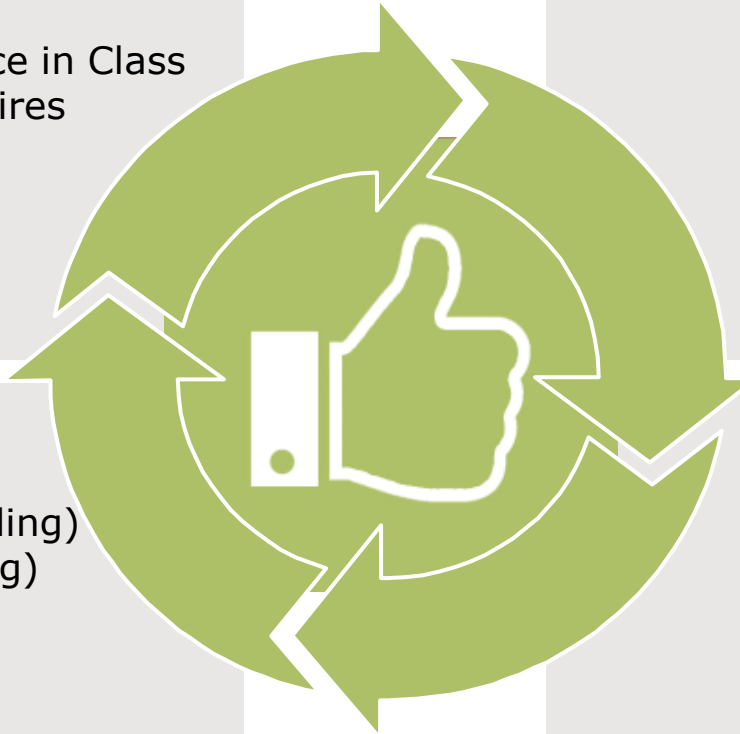
- › Double Side Cooling
- › Very low Top Side  $R_{th}$  enables Cooling via CAN to Heatsink

## Quality

- › Fully AECQ qualified
- › Proven IOL (Power Cycling) and TCoB (Temp Cycling) Reliability

## PCB

- › Standard FR4
- › Reduced PCB Temperature



# Limitations of DirectFET2

## Disadvantages

### PCB & Assembly

- › Increased PCB Temperature
- › Layout Inflexibility
- › Deviations of Body's Height:  
No Homogeneous  
Placement of  
Thin Thermal Adhesive

### Parallel Switching Performance

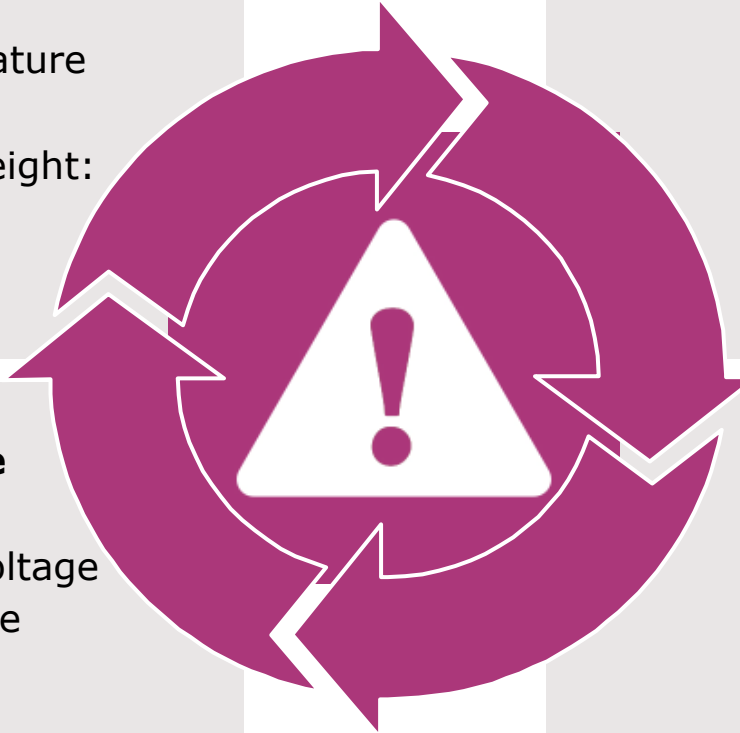
- › Parameter Variation
  - › Gate-Threshold Voltage
  - › Breakdown Voltage

### Market

- › Unique
- › No Footprint  
Compatible Alternatives

### Power Cycling

- › Bottle Neck :  
Bottom-Side Solder  
Bumps  
(High Thermal Stress)



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## Power MOS Chip Embedding – from Chip to System PCB



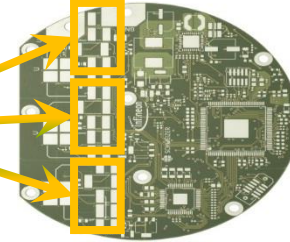
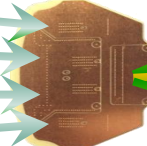
Chip

Standard Cell

p<sup>2</sup>pack

Smart p<sup>2</sup>pack

System



### Chip Embedding: Cross Section



### Chip Embedding: Increasing System Performance

- Low Ohmic Conductivity +++
- Low Inductive Switching +++
- System Cooling +++
- System Miniaturization +++
- System Assembly +++



## System Dimensions/Design

- › Compact Design Miniaturization
- › PCB Space Savings

## Power/Power Losses

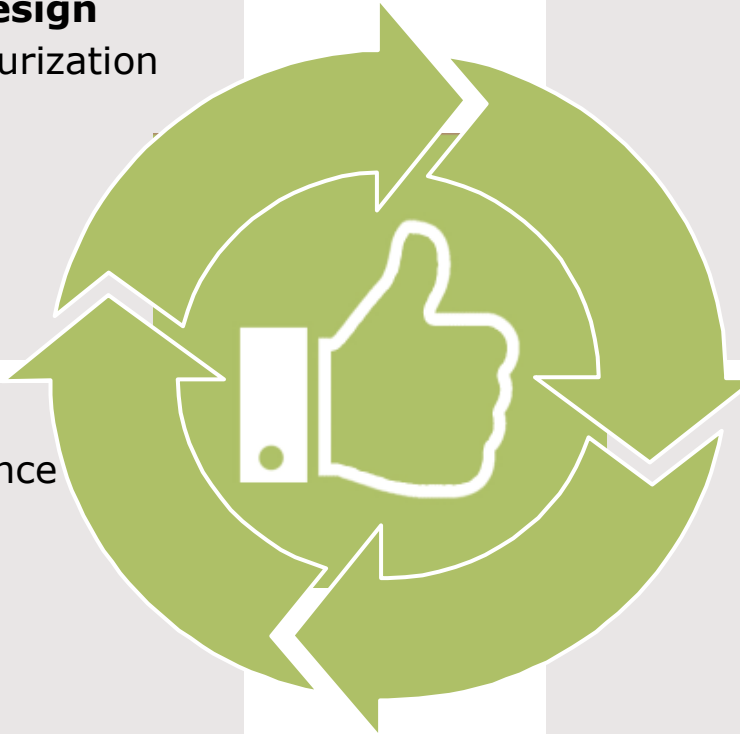
- › Low  $R_{ds(on)}$
- › Low  $R_{th}$
- › High Power Density

## Switching

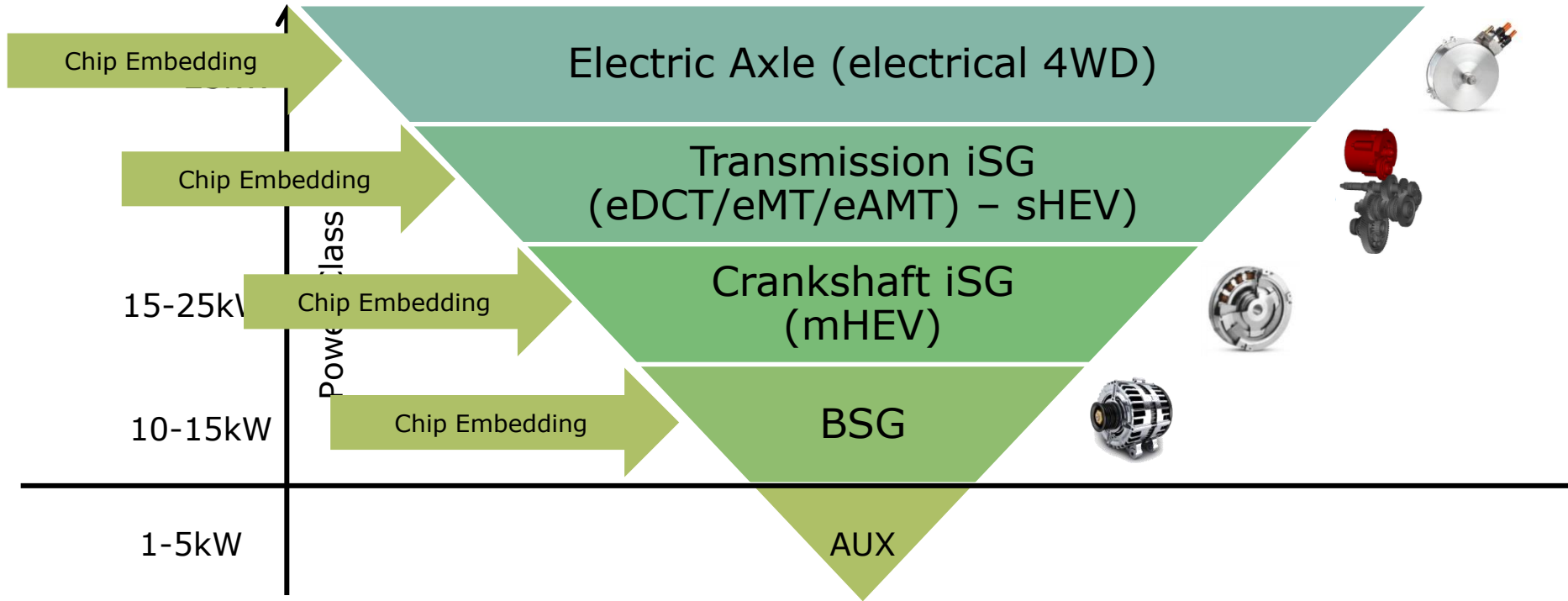
- › Reduced Stray Inductance
- › Fast Switching
- › Better EMC

## Quality

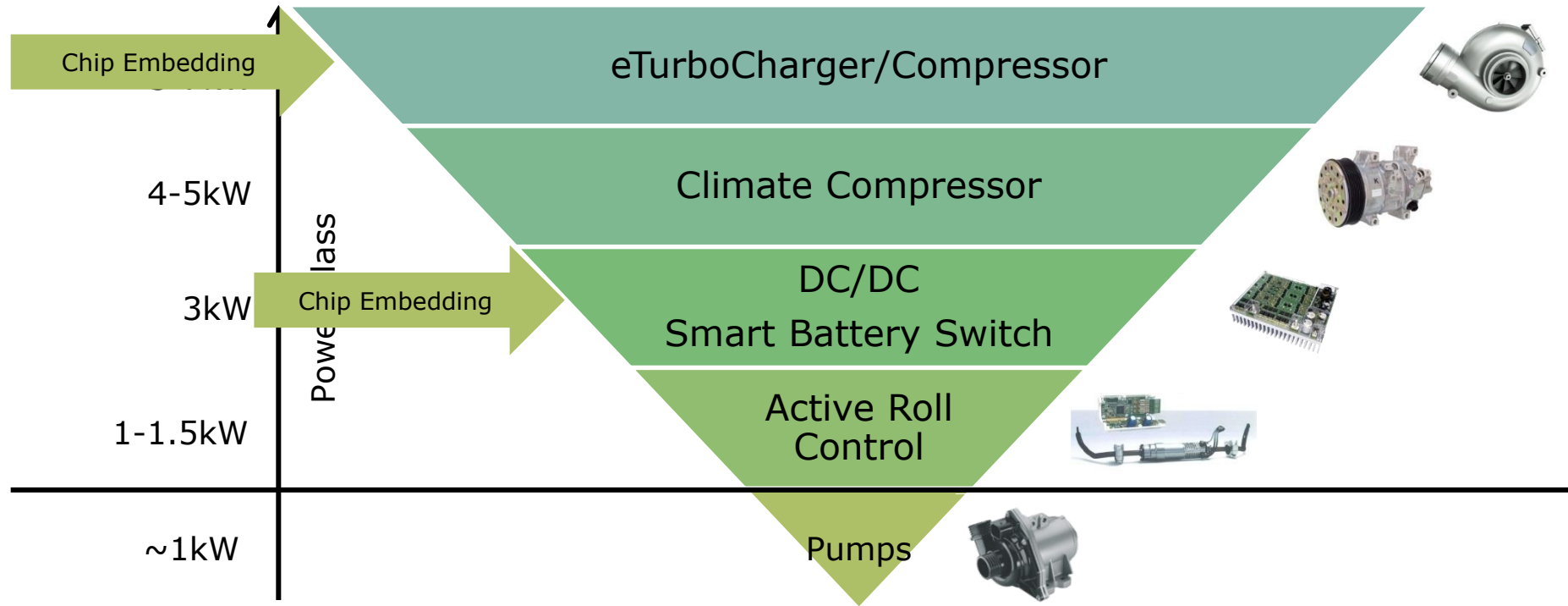
- › Increased Reliability



# High Power Inverters μHybridization



# High Power Inverters Auxiliary Drives



# Power MOS Chip-Embedding

## Potential System Improvements & Savings

Ceramic Board or Power PCB +  
Logic PCB = become only one PCB



**Save Connectors and  
Enhance Interconnects**

Better thermal & electrical  
Performance



**Save Cooling**

Reduction of Chip Size and / or  
Lower Voltage Class



**Save Semiconductor Costs**

Faster Switching possible



**Save Passives**

EMC Shielding with Cu-Layers



**Save EMC Measures**

Power stages are already insulated



**Save Insulator**

Miniaturization - Less Space



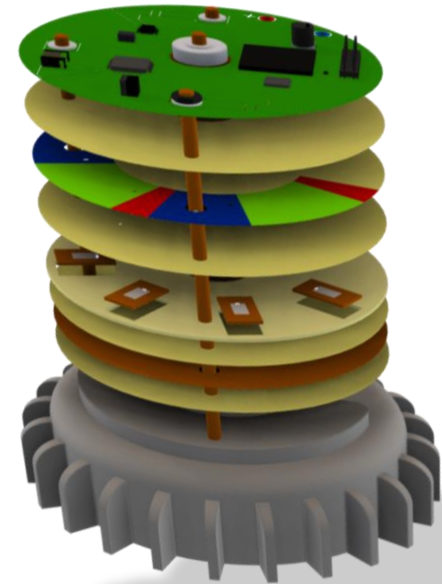
**Save Room/Space constrains  
“Money in Hybrid Cars”**

DC Link close to power stages



**Save System Costs**

**→ Optimizing System Performance & System Costs**



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# Comparison Module/CE/Discrete/TOLL-TOLT On Application Level

	Air cooling (**)	External Water Cooling (***)
		<b>TOLL/TOLG on IMS</b> (105µmCu, 2mm Al)
R <sub>thJH</sub> [K/W]		2
R <sub>thJH</sub> Improvement [%]		-
T <sub>J,max</sub> [°C]		175
T <sub>a,max</sub> [°C]		110
DT [K]		65
R <sub>pcck</sub> [mOhm]		0,16
R <sub>pcck</sub> [%]		-
R <sub>DSon,max25°C</sub> [mOhm]		1,5
R <sub>DSon,max25°C</sub> Improvement [%]		-
L <sub>s</sub> [nH]		2
L <sub>s</sub> Improvement [%]		-
Switching losses		30%
Max current ratings RMS [A]		95
Current Improvement [%]		-
		Reference:

(\*) Concept - based on Simulation

(\*\*) Low Budget Cooling

(\*\*\*) High End Cooling

# Comparison Module/CE/Discrete/TOLL-TOLT On Application Level

	Air cooling (**)	External Water Cooling (***)
	DCB	TOLL/TOLG on IMS
	Wedge bonded 175µm Si	(105µmCu, 2mm Al)
R <sub>thJH</sub> [K/W]	2	2
R <sub>thJH</sub> Improvement [%]	0%	-
T <sub>J,max</sub> [°C]	175	175
T <sub>a,max</sub> [°C]	110	110
DT [K]	65	65
R'' <sub>pck</sub> [mOhm]	0,5	0,16
R'' <sub>pck</sub> [%]	213%	-
R <sub>DSon,max25°C</sub> [mOhm]	1,84	1,5
R <sub>DSon,max25°C</sub> Improvement [%]	23%	-
L <sub>s</sub> [nH]	5	2
L <sub>s</sub> Improvement [%]	150%	-
Switching losses	40%	30%
Max current ratings RMS [A]	84	95
Current Improvement [%]	-12%	-
		Reference:

(\*) Concept - based on Simulation

(\*\*) Low Budget Cooling

(\*\*\*) High End Cooling

# Comparison Module/CE/Discrete/TOLL-TOLT On Application Level

	Air cooling (**)		External Water Cooling (***)	
	DCB	DCB	TOLL/TOLG on IMS (105µmCu, 2mm Al)	
	Wedge bonded 175µm Si	Wedge bonded 175µm Si		
R <sub>thJH</sub> [K/W]	2	1	2	
R <sub>thJH</sub> Improvement [%]	0%	-50%	-	
T <sub>J,max</sub> [°C]	175	175	175	
T <sub>a,max</sub> [°C]	110	110	110	
DT [K]	65	65	65	
R <sub>”pck”</sub> [mOhm]	0,5	0,5	0,16	
R <sub>”pck”</sub> [%]	213%	213%	-	
R <sub>DSon,max25°C</sub> [mOhm]	1,84	1,84	1,5	
R <sub>DSon,max”25°C</sub> Improvement [%]	23%	23%	-	
L <sub>s</sub> [nH]	5	5	2	
L <sub>s</sub> Improvement [%]	150%	150%	-	
Switching losses	40%	40%	30%	
Max current ratings RMS [A]	84	117	95	
Current Improvement [%]	-12%	23%	-	
			Reference:	

(\*) Concept - based on Simulation

(\*\*) Low Budget Cooling

(\*\*\*) High End Cooling



# Comparison Module/CE/Discrete/TOLL-TOLT On Application Level

	Air cooling (**)		External Water Cooling (***)	
	DCB	DCB	DCB (*)	TOLL/TOLG on IMS
	Wedge bonded 175µm Si	Wedge bonded 175µm Si	SFS 70µm Si	(105µmCu, 2mm Al)
R <sub>thJH</sub> [K/W]	2	1	0,9	2
R <sub>thJH</sub> Improvement [%]	0%	-50%	-55%	-
T <sub>J,max</sub> [°C]	175	175	175	175
T <sub>a,max</sub> [°C]	110	110	110	110
DT [K]	65	65	65	65
R'' <sub>pck</sub> [mOhm]	0,5	0,5	0,12	0,16
R'' <sub>pck</sub> [%]	213%	213%	-25%	-
R <sub>DSon,max25°C</sub> [mOhm]	1,84	1,84	1,46	1,5
R <sub>DSon,max''25°C</sub> Improvement [%]	23%	23%	-3%	-
L <sub>s</sub> [nH]	5	5	2	2
L <sub>s</sub> Improvement [%]	150%	150%	0%	-
Switching losses	40%	40%	30%	30%
Max current ratings RMS [A]	84	117	144	95
Current Improvement [%]	-12%	23%	52%	-
				Reference:

(\*) Concept - based on Simulation

(\*\*) Low Budget Cooling

(\*\*\*) High End Cooling

# Comparison Module/CE/Discrete/TOLL-TOLT On Application Level

	Air cooling (**)		External Water Cooling (***)		
	DCB	DCB	DCB (*)	TOLL/TOLG on IMS	CE (*)
	Wedge bonded 175µm Si	Wedge bonded 175µm Si	SFS 70µm Si	(105µmCu, 2mm Al)	
R <sub>thJH</sub> [K/W]	2	1	0,9	2	1
R <sub>thJH</sub> Improvement [%]	0%	-50%	-55%	-	-50%
T <sub>J,max</sub> [°C]	175	175	175	175	175
T <sub>a,max</sub> [°C]	110	110	110	110	110
DT [K]	65	65	65	65	65
R'' <sub>pck</sub> [mOhm]	0,5	0,5	0,12	0,16	0,1
R'' <sub>pck</sub> [%]	213%	213%	-25%	-	-38%
R <sub>DSon,max25°C</sub> [mOhm]	1,84	1,84	1,46	1,5	1,44
R <sub>DSon,max''25°C</sub> Improvement [%]	23%	23%	-3%	-	-4%
L <sub>s</sub> [nH]	5	5	2	2	"1"
L <sub>s</sub> Improvement [%]	150%	150%	0%	-	-50%
Switching losses	40%	40%	30%	30%	20%
Max current ratings RMS [A]	84	117	144	95	144
Current Improvement [%]	-12%	23%	52%	-	52%
				Reference:	

(\*) Concept - based on Simulation

(\*\*) Low Budget Cooling

(\*\*\*) High End Cooling

# Comparison Module/CE/Discrete/TOLL-TOLT On Application Level

	Air cooling (**)		External Water Cooling (***)			
	DCB	DCB	DCB (*)	TOLL/TOLG on IMS	CE (*)	Top Side Cooling (*)
	Wedge bonded 175µm Si	Wedge bonded 175µm Si	SFS 70µm Si	(105µmCu, 2mm Al)		
R <sub>thJH</sub> [K/W]	2	1	0,9	2	1	1,6
R <sub>thJH</sub> Improvement [%]	0%	-50%	-55%	-	-50%	-20%
T <sub>J,max</sub> [°C]	175	175	175	175	175	175
T <sub>a,max</sub> [°C]	110	110	110	110	110	110
DT [K]	65	65	65	65	65	65
R'' <sub>pck</sub> [mOhm]	0,5	0,5	0,12	0,16	0,1	0,16
R'' <sub>pck</sub> [%]	213%	213%	-25%	-	-38%	0%
R <sub>DSon,max25°C</sub> [mOhm]	1,84	1,84	1,46	1,5	1,44	1,5
R <sub>DSon,max25°C</sub> Improvement [%]	23%	23%	-3%	-	-4%	0%
L <sub>s</sub> [nH]	5	5	2	2	"1"	2
L <sub>s</sub> Improvement [%]	150%	150%	0%	-	-50%	0%
Switching losses	40%	40%	30%	30%	20%	30%
Max current ratings RMS [A]	84	117	144	95	144	107
Current Improvement [%]	-12%	23%	52%	-	52%	13%
				Reference:		

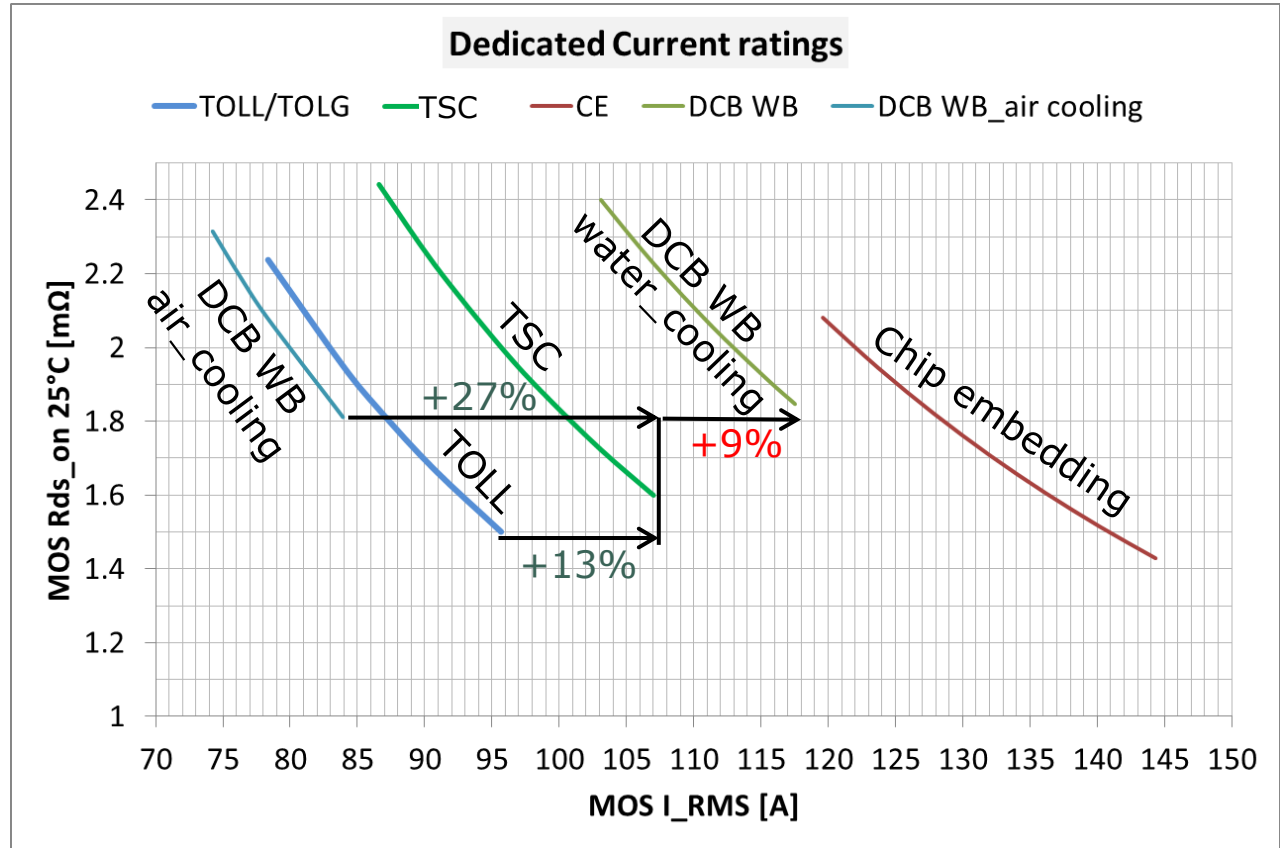
(\*) Concept - based on Simulation

(\*\*) Low Budget Cooling

(\*\*\*) High End Cooling

# Current Ratings Distribution According to Packages and Cooling Concept

- › 100V MOS  
 $R_{ds(on)}$ @25°C  
Vs  $I_{d\_RMS}$   
(Application  
Verification)



# Summary

## Comparison of MOSFET Solutions



	<b>TOLL TOLG</b>	<b>DirectFET2</b>	<b>Bare Die (Modules)</b>	<b>Chip Embedding (P<sup>2</sup>PAK)</b>
Technology	SFET5 ++	Gen10.7 +	SFET4 +	SFET5 ++
BiC Rds(on)	1.5mOhm (100V) 1.2mOhm (80V)	2.8mOhm (100V) 1.8mOhm (75V)	1.9mOhm (100V) 0.66mOhm (80V)	flexible
Space Consumption (based on 15kW 3 phase inverter)	4x 6 MOSFETs = 24 2880mm <sup>2</sup>	4x 6 MOSFETs = 24 1560mm <sup>2</sup>	30.24mm <sup>2</sup> /die * 2 (in parallel) * 6 = 362.88mm <sup>2</sup> (die space) + module	30mm <sup>2</sup> / chip P <sup>2</sup> PAK can be integrated space- neutral (embedding) ++
Costs	+	+	-	--
Product Current (Single Chip)	300A +	124A -	272A 0	300A +

# Summary

## Comparison of MOSFET Solutions



	<b>TOLL TOLG</b>	<b>DirectFET2</b>	<b>Bare Die (Modules)</b>	<b>Chip Embedding (P<sup>2</sup>PAK)</b>
Customization: differentiation to the competition	-	+	++	++
Layout flexibility	0	0	++	++
Handling	+	0	-	0
Portability from one gen to the next	++	0	-	++ (TIER1)



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